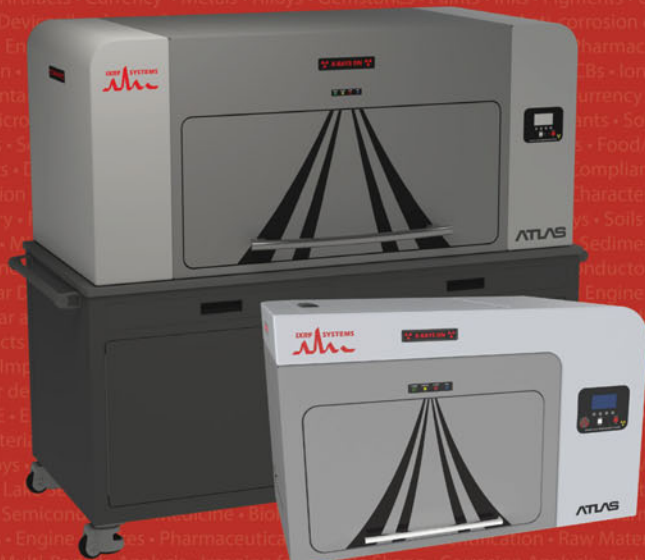

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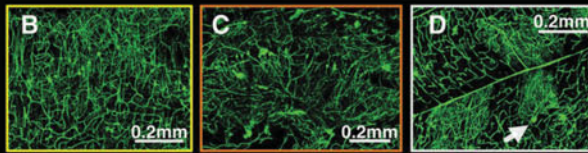
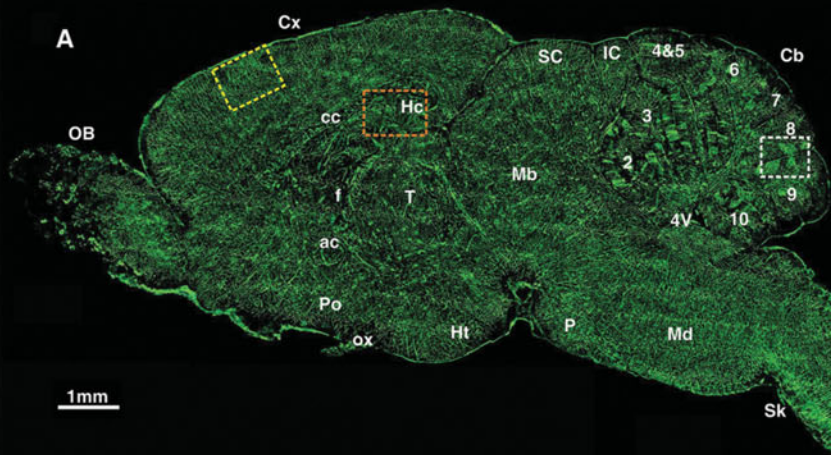
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(A) A sagittal image reconstructed from a stack of 100 virtual sagittal sections (total thickness of 0.1 mm). These sections were transformed from the original coronal sections. The sagittal image was located in the right hemisphere about 0.4 mm lateral to the middle. Almost all major regions of the brain can be seen in this image, e.g., the Olfactory Bulb (OB), Cerebral Cortex (Cx), Hippocampus (Hc), Fornix(f), Anterior Commissure (ac), Thalamus (T), Cerebellum (Cb), Midbrain (Mb), Pons (P), Medulla (Md), Corpus Callosum (cc), Superior Colliculus (SC), Inferior Colliculus (IC), Hypothalamus (Ht), Preoptic Area (Po), Optic Chiasm (ox), 4th ventricle (4V) and nine lobules of the cerebellum (Arabic numerals, 2 to 10). The three regions inside the different colored rectangle in (A) are the positions of (B), (C) and (D), which illustrate the cerebral cortex, hippocampus and cerebellum, respectively. In the reconstruction of sagittal image, no dislocation was observed along the D-V axis, i.e., the coronal sections are inherently aligned along the A-P axis.

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A 3D structural dataset of a Golgi-stained whole mouse brain at the neurite level was obtained. The morphology and spatial locations of neurons and traces of neurites were clearly distinguished. Researchers found that neighboring Purkinje cells were sticking to each other.

Acknowledgement

Micro-Optical Sectioning Tomography to Obtain a High-Resolution Atlas of the Mouse Brain Anan Li, Hui Gong, Bin Zhang, Qingdi Wang, Cheng Yan, Jingpeng Wu, Qian Liu, Shaoqun Zeng, Qingming Luo

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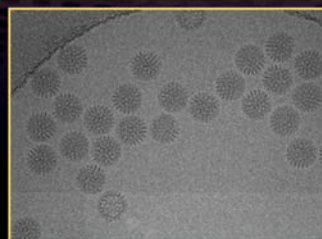
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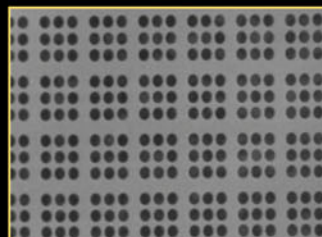
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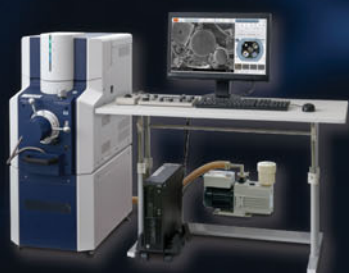
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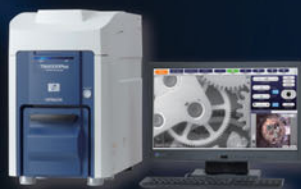
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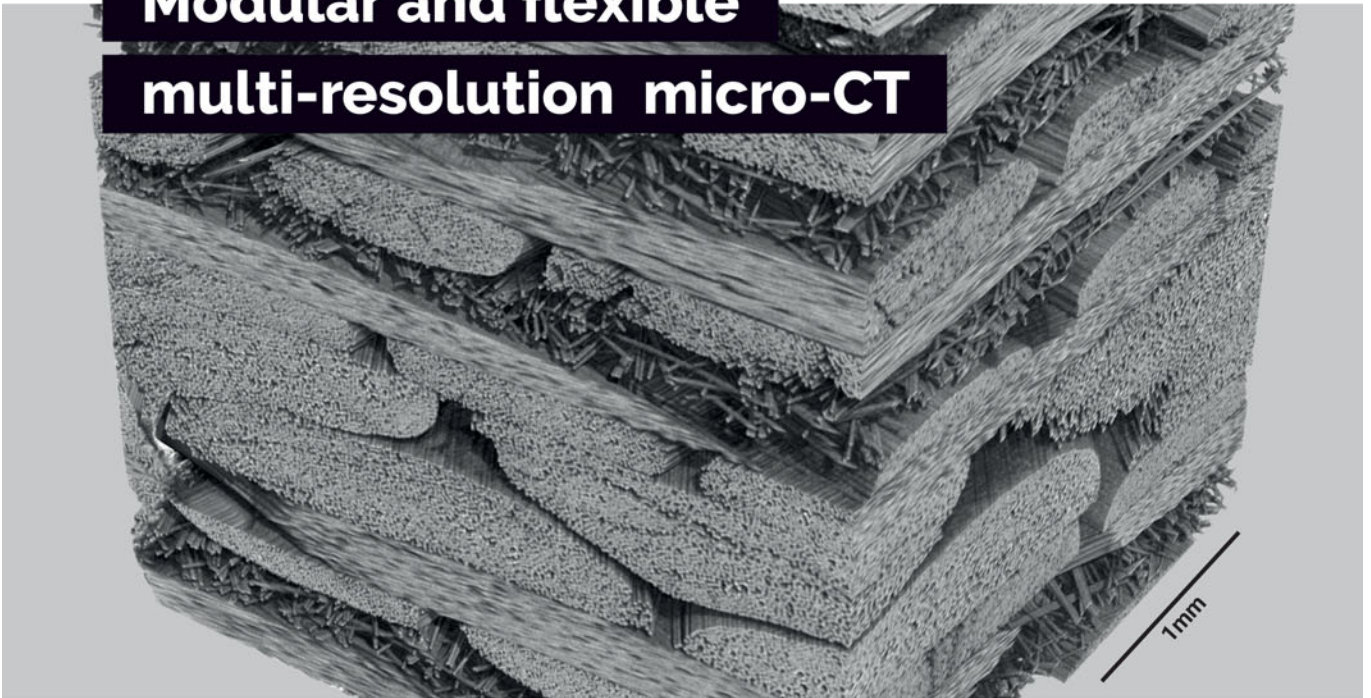


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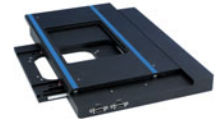
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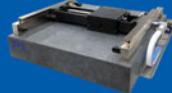
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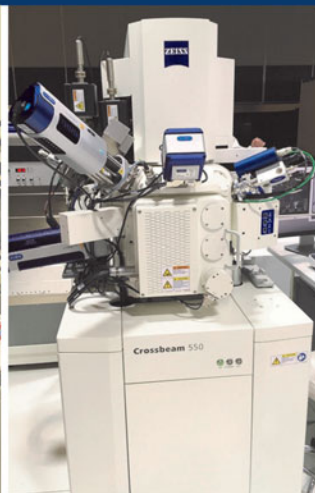
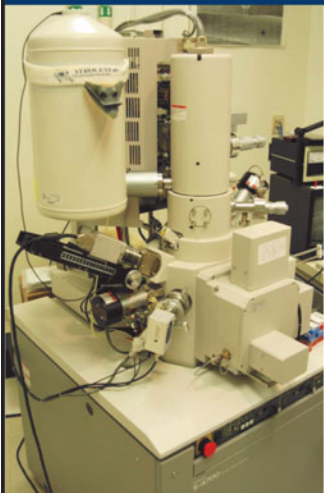
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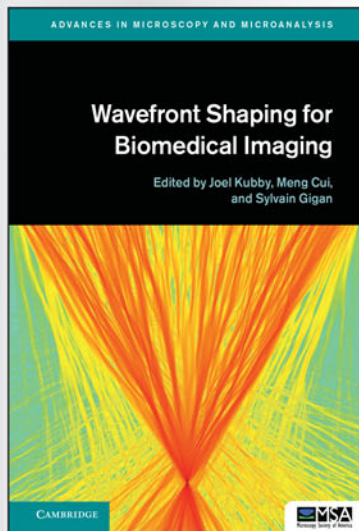
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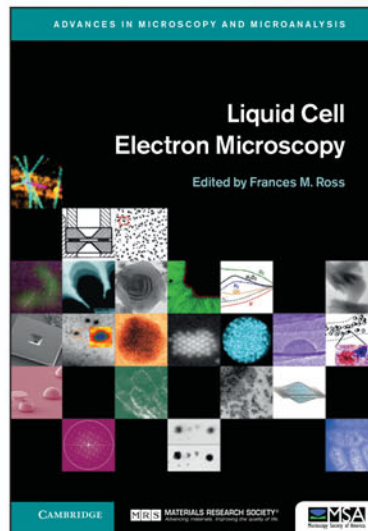
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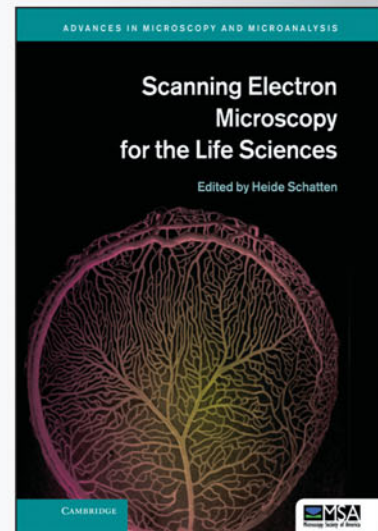
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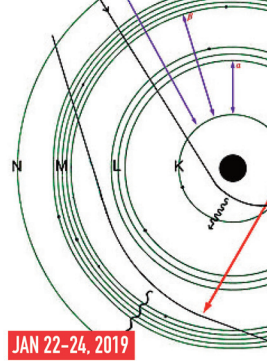
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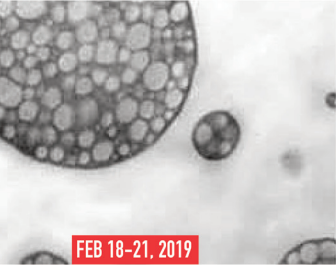
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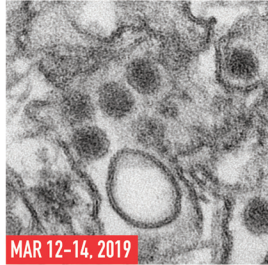
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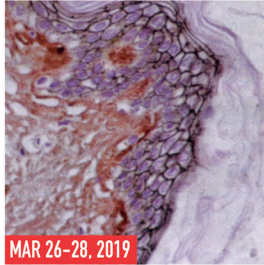
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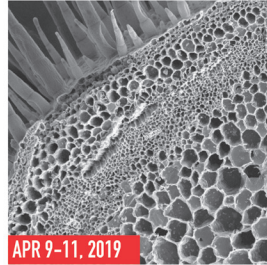
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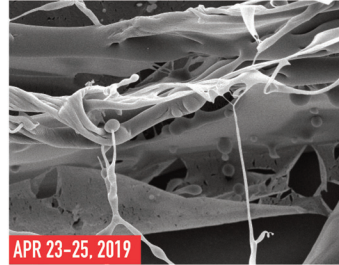
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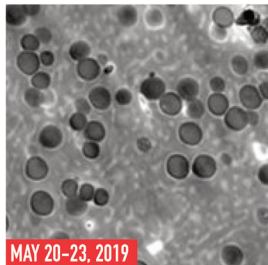
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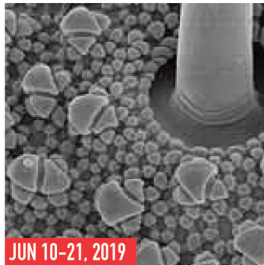
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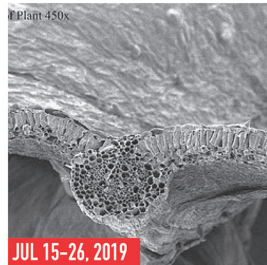
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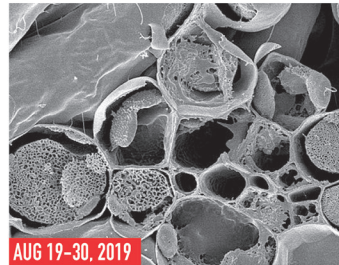
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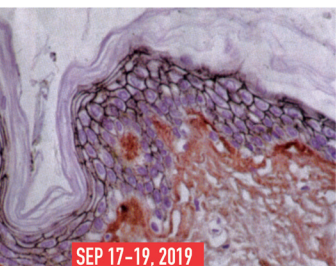
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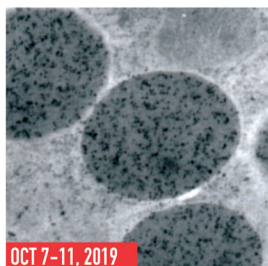
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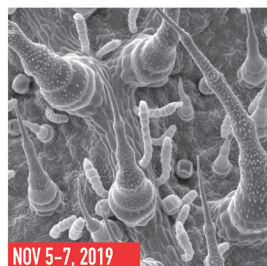
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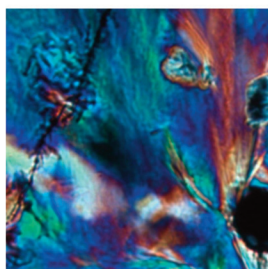
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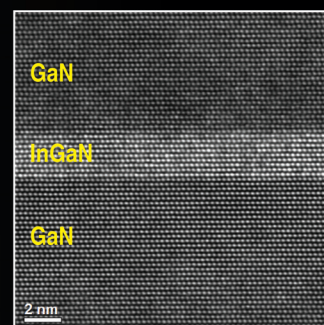
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